



# Atomic force microscopy /scanning tunneling microscopy 2 /

Cohen, Samuel H.  
Lightbody, Marcia L.

Springer Science+Business Media,  
1997

Conference papers and proceedings. Natick (Mass., 1994)

Monografía

This book represents the compilation of papers presented at the second Atomic Force Microscopy/Scanning Tunneling Microscopy (AFM/STM) Symposium, held June 7 to 9, 1994, in Natick, Massachusetts, at Natick Research, Development and Engineering Center, now part of U. S. Army Soldier Systems Command. As with the 1993 symposium, the 1994 symposium provided a forum where scientists with a common interest in AFM, STM, and other probe microscopies could interact with one another, exchange ideas and explore the possibilities for future collaborations and working relationships. In addition to the scheduled talks and poster sessions, there was an equipment exhibit featuring the newest state-of-the-art AFM/STM microscopes, other probe microscopes, imaging hardware and software, as well as the latest microscope-related and sample preparation accessories. These were all very favorably received by the meeting's attendees. Following opening remarks by Natick's Commander, Colonel Morris E. Price, Jr., and the Technical Director, Dr. Robert W. Lewis, the symposium began with the Keynote Address given by Dr. Michael F. Crommie from Boston University. The agenda was divided into four major sessions. The papers (and posters) presented at the symposium represented a broad spectrum of topics in atomic force microscopy, scanning tunneling microscopy, and other probe microscopies

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**Título:** Atomic force microscopy/scanning tunneling microscopy 2 edited by Samuel H. Cohen and Marcia L. Lightbody

**Editorial:** New York Springer Science+Business Media 1997

**Descripción física:** 1 online resource (ix, 250 pages) illustrations

**Variantes del título:** Atomic force microscopy/scanning tunneling microscopy two

**Nota general:** "Proceedings of the Second U.S. Army Soldier Systems Command, Natick Research, Development, and Engineering Center Atomic Force Microscopy/Scanning Tunneling Microscopy (AFM/STM) Symposium, held June 7-9, 1994, in Natick, Massachusetts"--Title page verso

**Bibliografía:** Includes bibliographical references and index

**Contenido:** Scanned probe microscopy / Michael F. Crommie -- Scanning tunneling microscopy for Very Large-Scale Integration (VLSI) Inspection / Shane Y. Hong -- Scanning tunneling microscopy-based fabrication of nanometer scale structures / Munir H. Nayfeh -- A microscopy for our time / Elinor Solit -- Scanning tunneling microscopy of chemical vapor deposition diamond film growth on highly oriented pyrolytic graphite and silicon / A. F. Aviles [and others] -- Scanning tunneling microscopy and atomic force microscopy of chemical-vapor-deposition diamond and diamond-like carbon thin films / T.W. Mercer [and others]

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**ISBN:** 9781475793253 electronic bk.) 1475793251 electronic bk.) 1475793278 9781475793277 9781475793277

**Materia:** Atomic force microscopy- Congresses Scanning tunneling microscopy- Congresses Microscopie à force atomique- Congrès Microscopie à effet tunnel- Congrès Atomic force microscopy. Scanning tunneling microscopy. Kongress. Rasterkraftmikroskopie. Rastertunnelmikroskopie.

**Autores:** Cohen, Samuel H. Lightbody, Marcia L.

**Congresos:** U.S. Army Soldier Systems Command, Natick Research, Development, and Engineering Center Atomic Force Microscopy/Scanning Tunneling Microscopy (AFM/STM) Symposium 2nd :. 1994 :. Natick, Mass.)

**Enlace a formato físico adicional:** Printed edition 9781475793277

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## Baratz Innovación Documental

- Gran Vía, 59 28013 Madrid
- (+34) 91 456 03 60
- [informa@baratz.es](mailto:informa@baratz.es)